CALL FOR PAPERS

62nd Annual Conference on Applications of X-ray Analysis
The Denver X-ray Conference
5–9 August 2013
The Westin Westminster
Westminster, Colorado, U.S.A.

Plenary Session
The 100th Anniversary of X-ray Spectroscopy

Training & Applications
Techniques & Instrumentation
Exhibits, Workshops, Sessions
Free CD of the Proceedings

Sponsored by International Centre for Diffraction Data

DEADLINE FOR SUBMISSION OF ABSTRACTS
15 February 2013
Abstracts are hereby solicited for oral presentations in any of the special sessions listed, or the XRD and XRF poster sessions. Poster sessions will be held on Monday (XRD) and Tuesday (XRF) evening of conference week, in conjunction with the evening receptions.

Abstracts are submitted online. Please visit our website for abstract preparation guidelines and submission instructions: www.dxcicdd.com.

Please also monitor our website regularly for updates to the Technical Program.

SPECIAL SESSIONS & INVITED TALKS

Wednesday, Thursday & Friday 7–9 August 2013
The exact date and time of each session will not be determined until May 2013.

PLENARY SESSION (Please note that all Plenary talks are invited; contributed abstracts are not accepted for the Plenary Session):

THE 100TH ANNIVERSARY OF X-RAY SPECTROSCOPY
Chair: George J. Havrilla, Los Alamos National Laboratory, Los Alamos, NM

WDX: FROM ROENTGEN TO MOSELEY TO BRAGG TO SHERMAN TO JENKINS

THE ELECTRONIC AGE—EDX AND OTHER MODERN TECHNIQUES TO THE PRESENT AND BEYOND
Michael Mantler, Rigaku Corporation, Purkersdorf, Austria

XRD AND XRF

NEW DEVELOPMENTS IN XRD & XRF INSTRUMENTATION
Chairs: T. Fawcett, International Centre for Diffraction Data, Newtown Square, PA, fawcett@icdd.com
T.N. Blanton, Eastman Kodak Company Research Labs, Rochester, NY, thomas.blanton@kodak.com

Abstracts should be submitted by technical representatives of a manufacturer. They should discuss specifications, and applications concerning one of their newest and most important products. Talks should include comments about software, XRD and XRF equipment, and accessories. No mention of prices or a comparison with competitors’ products can be included.

APPLIED MATERIAL ANALYSIS
Chairs: T. Fawcett, International Centre for Diffraction Data, Newtown Square, PA, fawcett@icdd.com
T.N. Blanton, Eastman Kodak Company Research Labs, Rochester, NY, thomas.blanton@kodak.com

STRUCTURE DESIGN OF NEW CATHODE MATERIALS FOR LI-ION BATTERIES
E. Antipov, Moscow State University, Moscow, Russia

SPECIALIZED SESSION: CORE SHELL SPECTROSCOPY IN INDUSTRIAL CATALYSIS
Chairs: C. Segre, Illinois Institute of Technology, Chicago, IL, segre@iit.edu
B. Ravel, Brookhaven National Laboratory, Upton, NY and National Institute of Standards and Technology, bravel@bnl.gov

IMPACT OF REDUCTION TEMPERATURE ON Pt MORPHOLOGY IN SUPPORTED Pt ON ALUMINA CATALYSTS
S. Kelly, UOP LLC- A Honeywell Company, Des Plaines, IL
POLYMERS – FULL DAY
Chairs: B. Landes, Dow Chemical Company, Midland, MI, bglandes@dow.com
L. Liu, Dow Chemical Company, Freeport, TX, liu4@dow.com
INVITED SPEAKER(S) TO BE ANNOUNCED

APPLICATIONS OF XRD IN THE PETROLEUM INDUSTRY
Chairs: D. Simon, DES Consulting, Bartlesville, OK, desconsulting@sbcglobal.net
R.W. Morton, Phillips 66, Bartlesville, OK, bob.morton@P66.com
LONG RANGE ORDER INDEX—A NEW CONCEPT IN CRYSTALLITE DOMAIN SIZE
R.W. Morton, Phillips 66, Bartlesville, OK

STRESS ANALYSIS
Chairs: D. Brown, Los Alamos National Laboratory, Los Alamos, NM, dbrown@lanl.gov
T.R. Watkins, Oak Ridge National Laboratory, Oak Ridge, TN, watkinstr@ornl.gov
INVITED SPEAKER(S) TO BE ANNOUNCED

NEW DEVELOPMENTS IN RIETVELD ANALYSIS
Chair: M. Suchomel, APS—Argonne National Laboratory, Lemont, IL, suchomel@aps.anl.gov
INVITED SPEAKER(S) TO BE ANNOUNCED

HIGH ENERGY XRD
Chair: J. Almer, APS, Argonne National Laboratory, Argonne, IL, almer@aps.anl.gov
NON-DESTRUCTIVE LATTICE ORIENTATION MAPPING IN 3D USING HIGH ENERGY DIFFRACTION MICROSCOPY
R. Suter, Carnegie Mellon University, Pittsburgh, PA
A COMBINED APPROACH TO MAPPING ORIENTATIONS, STRAINS, AND VOIDS/CRACKS/INCLUSIONS DURING LOADING USING HIGH ENERGY X-RAYS
J. Schuren, Air Force Research Laboratory, Wright-Patterson Air Force Base, OH
PAIR DISTRIBUTION FUNCTION
Chair: L. Ehm, Stony Brook University—Mineral Physics Institute, Stony Brook, NY and Brookhaven National Laboratory, Upton, NY, lars.ehm@stonybrook.edu
TOTAL SCATTERING AND PAIR DISTRIBUTION FUNCTION ANALYSIS IN ENVIRONMENTAL NANOPARTICLES
F.M. Michel, Virginia Tech, Blacksburg, VA
HIGH PRESSURE INVESTIGATIONS OF MOLECULAR LIQUIDS USING PAIR DISTRIBUTION FUNCTION ANALYSIS
N. Rademacher, Goethe-Universität Frankfurt, Frankfurt, Germany

DEADLINE FOR SUBMISSION OF ABSTRACTS:
15 FEBRUARY 2013
XRF

Fusion & Industrial Applications of XRF
Chair: J.A. Anzelmo, Anzelmo & Associates, Inc., Madison, WI, jaanzelmo@aol.com
Co-chair: J. Thomas, Wyoming Analytical Labs, Laramie, WY, jthomas@wal-lab.com

XRF Applications in the Coal and Fly-ash Industries
J. Thomas, Wyoming Analytical Labs, Laramie, WY

Applications of XRF in the Petroleum Industry
Chair: A. Doyle, Pontifical Catholic University of Rio de Janeiro (PUC-Rio), Rio de Janeiro, Brazil, doyle@puc-rio.br

Title to be announced
A. Saavedra, Petrobras R&D Center, Rio de Janeiro, Brazil

Determination of Chlorine in Petroleum and its Derivatives by Energy Dispersive X-ray Fluorescence Spectrometry and a Critical Comparison with Other Analytical Techniques
R. Q. Aucélio, PUC-Rio, Rio de Janeiro, Brazil

Trace Analysis
Chair: M.A. Zaitz, IBM, Hopewell Junction, NY, zaitz@us.ibm.com

GIXRF and XAS at Trace Levels
F. Meirer, MiNALab/Fondazione Bruno Kessler, Trento, Italy

Hard X-ray Micro/Nano-Probe Beamline
G. Falkenberg, HASYLAB at DESY, Hamburg, Germany

Quantitative Analysis
Chair: L.L. Brehm, Dow Chemical Company, Midland, MI, llbrehm@dow.com

Quantitative XRF Analysis of Ambient and Source Air Filters
S.D. Kohl, Desert Research Institute, Reno, NV

Studies using TXRF for Analysis of Aerosols Containing Nanoparticles with Designed Shapes and those Produced from Fabric Testing
U. Fittschen, University of Hamburg, Hamburg, Germany

Evaluation of PANalytical’s Omnian Software for Quantitative X-ray Fluorescence Analysis of Polylefins
D. Burns, Dow Chemical Company, Freeport, TX

Applications for Portable XRF
Chair: K.A. Russell, Olympus Innov-X, Woburn, MA, kimberley.russell@olympusndt.com
Co-chair: W. Benzel, USGS, Denver, CO

Screening Counterfeit Parts in Defense Manufacturing with Portable XRF
W. Tomczykowski, DfR Solutions, LLC, Beltsville, MD

MICRO XRF
Chair: G.J. Havrilla, Los Alamos National Laboratory, Los Alamos, NM, havrilla@lanl.gov

Superconducting Microcalorimeters for Time-resolved and Other Photon-starved X-ray Spectroscopies
J. Uhlig, Department of Commerce/NIST, Boulder, CO

Confocal microXRF in Vacuum: Setup and Applications
C. Streli, TU Wien, Atominsttitut, Vienna, Austria

High Resolution X-ray Fluorescence Microscopy for Biology and Bionanotechnology: Challenges and Opportunities
S. Vogt, Argonne National Lab, Argonne, IL

Deadline for submission of abstracts: 15 February 2013
WORKSHOPS
Monday & Tuesday 5 & 6 August 2013
The exact date & time of each workshop will not be determined until May 2013. Please visit our website for information on workshop instructors, and a description for each workshop.

XRD & XRF
X-ray Optics
Fundamentals of Digital Signal Processing & X-ray Detectors

XRD
Polymers—full day
Introduction to Volume H
An Introduction to the New GSAS-II Crystallographic Analysis System—full day

XRF
Basic XRF
Sample Preparation of XRF
Energy Dispersive XRF
Quantitative Analysis—full day
Trace Analysis

REGISTRATION FEES
Please see our website for registration and cancellation policies.

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<thead>
<tr>
<th>Event</th>
<th>by 1 July</th>
<th>after 1 July</th>
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<tbody>
<tr>
<td>Full week: exhibits, workshops, sessions*</td>
<td>$600</td>
<td>$675</td>
</tr>
<tr>
<td>Monday &amp; Tuesday: exhibits, workshops*</td>
<td>$550</td>
<td>$625</td>
</tr>
<tr>
<td>Wednesday, Thursday &amp; Friday: exhibits, sessions*</td>
<td>$550</td>
<td>$625</td>
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<tr>
<td>Session Organizer, invited speaker &amp; workshop instructor*</td>
<td>$100</td>
<td>$100</td>
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<tr>
<td>Student (I.D. required), Unemployed, 65 and older</td>
<td>$225</td>
<td>$300</td>
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*Includes a copy of Volume 57, Advances in X-ray Analysis, on CD.

Also on our website: Hotel and Travel Details; Student Housing, Awards & Grants; Exhibits/Sponsorships; Conference Proceedings and Registration.

WWW.DXCICDD.COM
DATES TO REMEMBER

Exhibit space opens
1 February

Deadline for submission of abstracts
15 February

Conference Program available on-line
May

Deadline to submit for Cohen Student Award
1 June

Deadline for Pre-registration discount fee
1 July

Deadline to apply for a Student Room
1 July

Deadline to book host hotel room at conference rate
15 July

Deadline for submission of manuscripts
6 September